

Notice of References Cited	Application/Control No. 10/695,630		Applicant(s)/Patent Under Reexamination LIN ET AL	
	Examiner Alexander O. Williams		Art Unit 2826	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,787,442 B2	09-2004	Hayashida, Tetsuya	438/612
*	B	US-2003/0052409 A1	03-2003	Matsuo et al.	257/737
*	C	US-6,734,556 B2	05-2004	Shibata, Kazutaka	257/737
*	D	US-6,780,677 B2	08-2004	Imasu et al.	438/118
*	E	US-6,555,460	04-2003	Farnworth, Warren M.	438/614
*	F	US-6,875,638 B2	04-2005	Yoneda et al.	438/125
*	G	US-2003/0022479 A1	01-2003	Hayashida, Tetsuya	438/614
*	H	US-6,461,896	10-2002	Imasu et al.	438/108
*	I	US-6,798,058	09-2004	Hashimoto, Nobuaki	257/693
*	J	US-5,108,027	04-1992	Warner et al.	228/254
*	K	US-6,288,559 B1	09-2001	Bernier et al.	324/755
*	L	US-6,882,050 B2	04-2005	Tanaka, Yasuo	257/737
*	M	US-2002/0025655 A1	02-2002	Satoh et al.	438/460

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	64-7638	01-1989	Japan	Okuaki	
	O	8-148496	06-1996	Japan		
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.